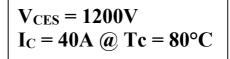
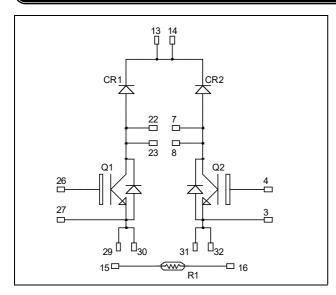
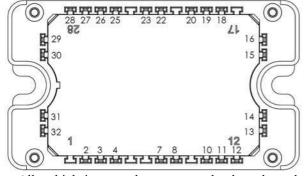


Dual Boost chopper High speed Trench + Field Stop IGBT4 Power Module







All multiple inputs and outputs must be shorted together Example: 13/14; 29/30; 22/23 ...

Application

- AC and DC motor control
- Switched Mode Power Supplies
- Power Factor Correction

Features

- High speed Trench + Field Stop IGBT 4
 - Low voltage drop
 - Low leakage current
 - Low switching losses
- Chopper SiC Schottky Diode (CR1, CR2)
 - Zero reverse recovery
 - Zero forward recovery
 - Temperature Independent switching behavior
 - Positive temperature coefficient on VF
- Kelvin emitter for easy drive
- Very low stray inductance
- Internal thermistor for temperature monitoring

Benefits

- Stable temperature behavior
- Very rugged
- Solderable terminals for easy PCB mounting
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Easy paralleling due to positive TC of VCEsat
- Low profile
- RoHS Compliant

All ratings @ $T_j = 25^{\circ}C$ unless otherwise specified

Q1, Q2 Absolute maximum ratings (per IGBT)

Symbol	Parameter		Max ratings	Unit
V_{CES}	Collector - Emitter Voltage		1200	V
Ţ	Continuous Collector Current	$T_C = 25^{\circ}C$	75	
$I_{\rm C}$	$T_{\rm C} = 80^{\circ}{\rm C}$	$T_C = 80^{\circ}C$	40	Α
I_{CM}	Pulsed Collector Current	$T_C = 25^{\circ}C$	160	
V_{GE}	Gate – Emitter Voltage		±20	V
P_{D}	Power Dissipation		250	W

These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

CAUTION:



Q1, Q2 Electrical Characteristics (per IGBT)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
I_{CES}	Zero Gate Voltage Collector Current	$V_{GE} = 0V$, $V_{CE} =$			100	μΑ	
17	Collector Emitter Saturation Voltage	$V_{GE} = 15V$	$T_j = 25$ °C	1.7	2.05	2.4	V
V _{CE(sat)}	Conector Emitter Saturation Voltage	$I_C = 40A$	$T_j = 150$ °C		2.6		V
$V_{GE(th)}$	Gate Threshold Voltage	$V_{GE} = V_{CE}, I_C = 1 \text{ mA}$		5.0	5.8	6.5	V
I_{GES}	Gate – Emitter Leakage Current	$V_{GE} = 20V, V_{CE}$	=0V			120	nA

Q1, Q2 Dynamic Characteristics (per IGBT)

Symbol	Characteristic	Test Conditions		Min	Тур	Max	Unit
Cies	Input Capacitance	$V_{GE} = 0V$ $V_{CE} = 25V$			2300		
Coes	Output Capacitance				150		pF
C_{res}	Reverse Transfer Capacitance	f = 1MHz			135		
Q_{G}	Gate charge	$V_{GE} = 15V, I_C = 40$ $V_{CE} = 960V$	A		185		nC
$T_{d(on)}$	Turn-on Delay Time	Inductive Switchin	g (25°C)		30		
$T_{\rm r}$	Rise Time	$V_{GE} = \pm 15V$			57		ns
T _{d(off)}	Turn-off Delay Time	$V_{\text{Bus}} = 600V$ $I_{\text{C}} = 40A$			290		
T_{f}	Fall Time	$R_G = 12\Omega$			16		
T _{d(on)}	Turn-on Delay Time	Inductive Switching (150°C) $V_{GE} = \pm 15V$ $V_{Bus} = 600V$ $I_{C} = 40A$			30		ns
T_{r}	Rise Time				49		
$T_{d(off)} \\$	Turn-off Delay Time				366		
T_{f}	Fall Time	$R_G = 12\Omega$			48		
Б	T	$V_{GE} = \pm 15V$ T	$_{\rm j} = 25^{\circ}{\rm C}$		1.9		
Eon	Turn on Energy	$V_{Bus} = 600V$ $T_{j} = 150^{\circ}C$ $T_{j} = 25^{\circ}C$			2.25		Т
E	T				1.2		mJ
$E_{\rm off}$	Turn off Energy	$R_G = 12\Omega$ T_j	= 150°C		2.25		
I_{sc}	Short Circuit data	$V_{GE} \le 15V ; V_{Bus} = t_p \le 10 \mu s ; T_j = 150^{\circ}$			150		A
R_{thJC}	Junction to Case Thermal Resistance					0.6	°C/W

CR1, CR2 chopper SiC diode ratings and characteristics (per diode)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit		
V_{RRM}	Peak Repetitive Reverse Voltage					1200	V		
I_{RM}	Reverse Leakage Current	$V_{p}=1200V_{p}$	$T_j = 25$ °C		150	600	μA		
	7.7		$T_{j} = 175^{\circ}C$		300	3000			
I_{F}	DC Forward Current		Tc = 100°C		15		Α		
V_{F}	V _F Diode Forward Voltage I	$I_{\rm F} = 15A$	$T_j = 25^{\circ}C$		1.6	1.8	V		
٧ г	Blode I of ward Vollage	1 _F 1371	T _F 1371	$T_j = 175$ °C	$T_j = 175$ °C		2.6	3	,
$Q_{\rm C}$	Total Capacitive Charge	$I_F = 15A, V_R = 600V$ $di/dt = 1000A/\mu s$			42		nC		
C	Total Capacitance	$f = 1MHz, V_R =$	200V		135		рF		
	Total Capacitance	$f = 1MHz, V_R =$	400V		99		hr.		
R_{thJC}	Junction to Case Thermal Resistance					1	°C/W		



IGBT protection diode ratings and characteristics (per diode) Symbol Characteristic Test Conditions

Symbol	Characteristic	Test Conditions	!	Min	Тур	Max	Unit
V_{RRM}	Peak Repetitive Reverse Voltage					1200	V
I_{RM}	Reverse Leakage Current	V _R =1200V				250	μΑ
I_{F}	DC Forward Current		Tc = 80°C		25		A
		$I_F = 25A$			2.6	3.1	
V_{F}	Diode Forward Voltage	$I_F = 50A$			3.2		V
		$I_F = 25A$	$T_j = 125$ °C		1.8		
+	Reverse Recovery Time		$T_j = 25$ °C		320		12 G
t_{rr}		$I_F = 25A$	$T_j = 125$ °C		360		ns
Qrr	Reverse Recovery Charge	$V_R = 667V$ di/dt = 200A/\(\mu\)s	$T_j = 25$ °C		480		пC
			$T_j = 125$ °C		1800		пС
R_{thJC}	Junction to Case Thermal Resistance					1.4	°C/W

Temperature sensor NTC (see application note APT0406 on www.microsemi.com).

Symbol	Characteristic		Min	Typ	Max	Unit
R ₂₅	Resistance @ 25°C			50		kΩ
$\Delta R_{25}/R_{25}$				5		%
$B_{25/85}$	$T_{25} = 298.15 \text{ K}$			3952		K
$\Delta \mathrm{B/B}$		T _C =100°C		4		%

$$R_T = \frac{R_{25}}{\exp \left[B_{25/85} \left(\frac{1}{T_{25}} - \frac{1}{T} \right) \right]}$$
 T: Thermistor temperature R_T: Thermistor value at T

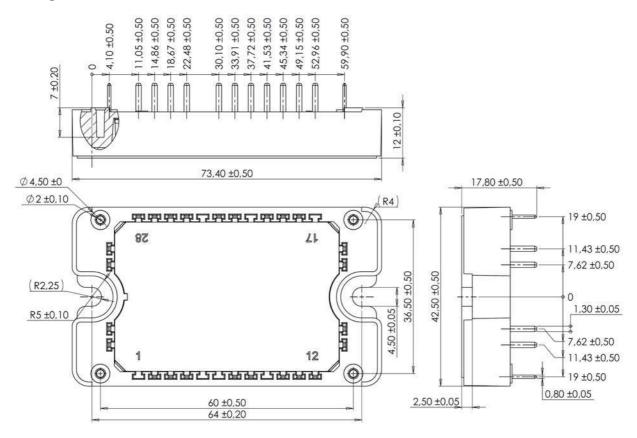
Thermal and package characteristics

The mar and parents of characteristics								
Symbol	Characteristic			Min	Max	Unit		
V_{ISOL}	RMS Isolation Voltage, any terminal to case	t = 1 min, 50/60)Hz	4000		V		
$T_{\rm J}$	Operating junction temperature range			-40	175*			
T_{JOP}	Recommended junction temperature under sv	-40	T _J max -25	°C				
T_{STG}	Storage Temperature Range	-40	125					
$T_{\rm C}$	Operating Case Temperature			-40	125			
Torque	Mounting torque	To heatsink	M4	2	3	N.m		
Wt	Package Weight				110	g		

^{*} T_J =150°C for the IGBT protection diode

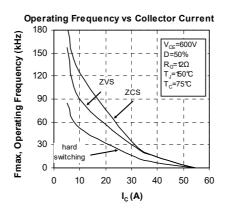


Package outline (dimensions in mm)



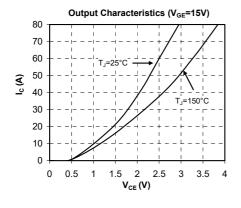
See application note 1906 - Mounting Instructions for SP3F Power Modules on www.microsemi.com

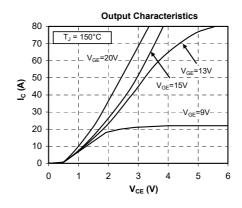
Typical Performance Curve IGBT

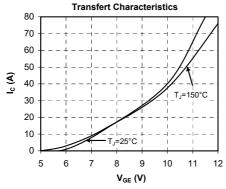


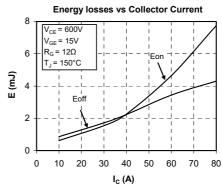


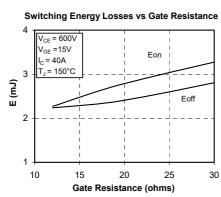
Power Matters."

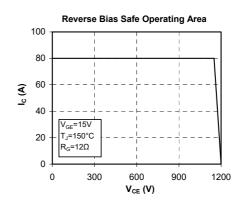


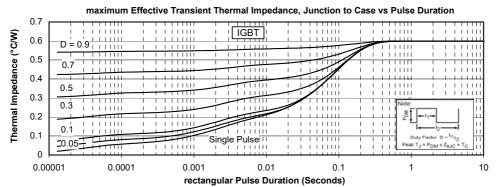








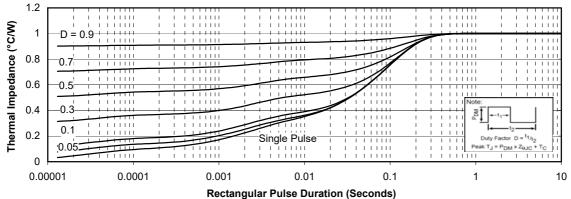


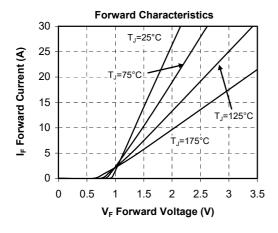


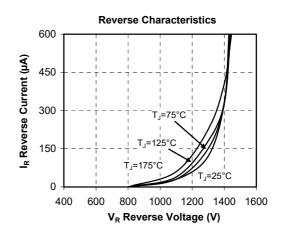


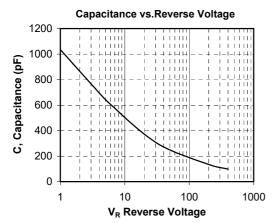
Chopper SiC diode

Maximum Effective Transient Thermal Impedance, Junction to Case vs Pulse Duration











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